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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/910,371	07/20/2001	John E. Seem	510554.95814	2802
26371	7590 04/11/2003			•
FOLEY & LARDNER 777 EAST WISCONSIN AVENUE SUITE 3800			EXAMINER	
			WEST, JEFFREY R	
MILWAUKEE, WI 53202-5308			ART UNIT	PAPER NUMBER
			2857	
			DATE MAILED: 04/11/2003	

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant	t(s)		
		09/910,371	SEEM, JO	DHN E.		
Office Action Summary		Examiner	Art Unit			
		Jeffrey R. West	2857			
The N	IAILING DATE of this communication app	ears on the c ver she	et with the correspond	ence address		
THE MAILING - Extensions of till after SIX (6) MC - If the period for - If NO period for - Failure to reply - Any reply receive	IED STATUTORY PERIOD FOR REPLY G DATE OF THIS COMMUNICATION. me may be available under the provisions of 37 CFR 1.13 This from the mailing date of this communication. reply specified above is less than thirty (30) days, a reply reply is specified above, the maximum statutory period within the set or extended period for reply will, by statute, red by the Office later than three months after the mailing erm adjustment. See 37 CFR 1.704(b).	6(a). In no event, however, m within the statutory minimum ill apply and will expire SIX (6) cause the application to become	ay a reply be timely filed of thirty (30) days will be consid MONTHS from the mailing dat ne ABANDONED (35 U.S.C. §	te of this communication.		
1)⊠ Respo	onsive to communication(s) filed on	<u>.</u> .				
2a)☐ This a	nction is FINAL. 2b)⊠ Thi	s action is non-final.				
	this application is in condition for allowa d in accordance with the practice under <i>l</i> claims					
, , ,	s) <u>1-19</u> is/are pending in the application.					
1	he above claim(s) is/are withdraw	n from consideration	•			
. 5) ☐ Claim(s	s) is/are allowed.					
	s) <u>1-19</u> is/are rejected.					
7) Claim(s	s) is/are objected to.					
1 '	s) are subject to restriction and/or	election requirement	•			
Application Pap						
1	cification is objected to by the Examiner					
	wing(s) filed on <u>20 July 2001</u> is/are: a)	• • •	-			
1	ant may not request that any objection to the posed drawing correction filed on	· ,	•	` ,		
	oved, corrected drawings are required in rep		disapproved by the	Examiner.		
	h or declaration is objected to by the Exa					
1	5 U.S.C. §§ 119 and 120					
<u> </u>	vledgment is made of a claim for foreign	priority under 35 LLS	C & 119(a)-(d) or (f)			
	o) Some * c) None of:	priority under 35 O.O	.o. 3 113(a)-(d) of (i).			
l	Certified copies of the priority documents	have been received				
	• • •					
2. Certified copies of the priority documents have been received in Application No3. Copies of the certified copies of the priority documents have been received in this National Stage						
	application from the International Bur attached detailed Office action for a list of	eau (PCT Rule 17.2(a)).	ational Stage		
14) Acknowl	edgment is made of a claim for domestic	priority under 35 U.S	S.C. § 119(e) (to a pro	visional application).		
	e translation of the foreign language provedgment is made of a claim for domestic	• •		1.		
Attachment(s)						
2) Notice of Draft	rences Cited (PTO-892) sperson's Patent Drawing Review (PTO-948) sclosure Statement(s) (PTO-1449) Paper No(s) <u>2</u> .		riew Summary (PTO-413) Fe of Informal Patent Applica			
U.S. Patent and Trademark Off PTO-326 (Rev. 04-01)		ion Summary	-	Part of Paper No. 5		

Art Unit: 2857

DETAILED ACTION

Drawings

1. The drawings are objected to as failing to comply with 37 CFR 1.84(p)(5) because they include the following reference sign(s) not mentioned in the description: "62" (Figure 4). A proposed drawing correction, corrected drawings, or amendment to the specification to add the reference sign(s) in the description, are required in reply to the Office action to avoid abandonment of the application. The objection to the drawings will not be held in abeyance.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 3. Claims 1-8 are rejected under 35 U.S.C. 103(a) as being unpatentable over U.S. Patent No. 4,990,893 to Kiluk in view of Carey et al., "Resistance and Test-Based Outlier Rejection: Effects on Gaussian One- and Two-Sample Inference."

Kiluk discloses a method in an alarm system, including recording of energy consumption, such as electricity, gas or water utility consumption (column 3, lines 4-10), by repeatedly measuring a level of use of a utility to produce a plurality of utility measurements (column 2, lines 48-51 and Figure 2). Kiluk then discloses comparing a current measurement to a corresponding reference value at the same

Art Unit: 2857

point in time. It is then determined whether the current measurement varies significantly (i.e. is an outlier) compared to the value and, if so determined, the severity of an abnormality in utility consumption is identified (i.e. evaluation of system performance) (column 2, line 57 to column 3, line 3). Although, Kiluk doesn't specifically disclose performing separate comparisons, Kiluk does provide the functionally equivalent method for comparing the measurement values to the reference values with groups defined by time periods of normally similar usage (column 3, lines 24-27), groups of days of normally similar usage, and groups dependent on changes in living habits (column 3, lines 46-61).

Although Kiluk teaches comparing the current measurements to reference values in order to determine significantly outlying data values, Kiluk doesn't provide a corresponding statistical method for determining what values are significantly outlying, specifically by using a GESD.

Carey teaches a method for outlier detection through the use of the Generalized Extreme Studentized Deviate (GESD) statistical procedure (page 326, column 2). Carey also teaches the definition of the GESD procedure comprising determining how many standard deviations a given outlier is from an average of the samples using the equation R1 = max $| X_i - X | / s$ where X_i is the amplitude of the i-th outlier, X is the average (i.e. mean) value of a plurality of samples, and s is the standard deviation. Carey also teaches determining the critical values using a common student t-distribution equation and determining the percentile using the equation $p = 1 - [(\alpha / 2) / (n - /)]$ (page 329). Carey also teaches determining an outlier, removing

Application/Control Number: 09/910,371

Art Unit: 2857

each outlier, and repeating the determining and removing steps until all outliers have been identified and removed (i.e. iterative peeling) (page 321, column 1).

Although not specifically disclosed, in order to used the equations previously described, it is considered inherent that the value X_i , corresponding to the current outlier, the value of X (i.e. mean), and the value of s (i.e. standard deviation) must all be previously determined since the equations require these initial values.

It would have been obvious to one having ordinary skill in the art to modify the invention of Kiluk to include determining what values are significantly outlying using a GESD, as taught by Carey, because the combination would have provided a method necessary in the invetion of Kiluk to discriminate between small changes in measurements and significant deviations which, as suggested by Carey, is a well known, accurate, method that explicitly follows error-based standardization and can be calibrated to possess any desired mislabeling rate (page 321, column 2).

4. Claims 9-18 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kiluk in view of Carey et al. and further in view of Sematech, "The Engineers Statistical Internet (ESI) Handbook: Grubbs' Test for Outliers."

As noted above, the invention of Kiluk and Carey teaches all the features of the claimed invention except for specifying what percent of a critical value indicates the occurrence of an outlier.

Sematech teaches the well-known definition of the Grubbs' statistic (also known as the GESD) for determining the largest absolute deviation from a sample mean in

units of the sample standard deviation. Sematech also teaches determining an outlier if it exists outside the critical regions wherein the critical regions are defined as having limits calculated as either 100α or 95α percent of the critical values.

It would have been obvious to one having ordinary skill in the art to modify the invention of Kiluk and Carey to include specifying that the confidence level be at 100% of the critical value, as taught by Sematech, because the combination would have provided a necessary value to indicate an outlier occurrence that would result in a high level of confidence. Further, although the Applicant describes the use of a 100% value in the specification, Applicant fails to provide the criticality for choosing this value. Therefore this feature is considered an engineering design choice and it would have been obvious to one having ordinary skill in the art to choose whatever confidence level desired in a specific implementation.

5. Claim 19 is rejected under 35 U.S.C. 103(a) as being unpatentable over Kiluk in view of Carey et al. and Sematech and further in view of U.S. Patent No. 5,555,195 to Jensen et al.

As noted above, the invention of Kiluk and Carey teaches all the features of the claimed invention except for specifying that maintenance be performed on the system in response to the examination of one or more of the outliers.

Jensen teaches a controller for use in an environment control network capable of storing diagnostic information comprising a processor for receiving a sensed parameter value, providing a summary value related to the parameter value, and

Application/Control Number: 09/910,371

'Art Unit: 2857

Page 6

storing the summary value in memory (column 2, lines 54-67). Jensen also teaches sending summary data indicative of the lifetime operation of the device being monitored to an operator for review (column 3, lines 16-23) wherein the operator views outliers in the data as devices requiring maintenance (column 9, lines 57-65).

It would have been obvious to one having ordinary skill in the art to modify the invention of Kiluk, Carey, and Sematech to include specifying that maintenance be performed on the system in response to the examination of one or more of the outlier, as taught by Jensen, because the invention of Kiluk, Carey, and Sematech teaches alarming the user to an abnormality when an outlier value is detected and, as suggested by Jensen, the combination would have provided a method for correcting the occurrence of errors and therefore restored proper operation (column 9, lines 57-65).

Conclusion

- 6. The prior art made of record and not relied upon is considered pertinent to Applicant's disclosure.
- U.S. Patent Application Publication No. 2003/0061249 to Ramaswamy et al. teaches a method for identifying abnormal usage patterns through the identification of outliers.
- U.S. Patent No. 6,424,929 to Dawes teaches a method for detecting outlier measures of activity.

Application/Control Number: 09/910,371

Art Unit: 2857

U.S. Patent Application Publication No. 2001/0020219 to Kishlock et al. teaches

an energy efficiency measuring system and reporting methods including determining

statistical deviations in normal usage.

U.S. Patent Application Publication No. 2003/0014205 to Tabor teaches a

method and apparatus for semiconductor testing including determining outliers and

examining the outliers to identify potentially unreliable components.

7. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Jeffrey R. West whose telephone number is

(703)308-1309. The examiner can normally be reached on Monday through Friday,

8:00-4:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Marc S. Hoff can be reached on (703)308-1677. The fax phone

numbers for the organization where this application or proceeding is assigned are

(703)308-7382 for regular communications and (703)308-7382 for After Final

communications.

Any inquiry of a general nature or relating to the status of this application or

proceeding should be directed to the receptionist whose telephone number is

(703)308-0956.

MARC S. HOUFF SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800 Page 7

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April 6, 2003